

## **Certificate of Approval**

**AWARDED TO** 

Texas Instruments, Inc. - LFAB
4000 N Flash Drive Lehi, UT 84043 United States
IATF USI: L9MWCR

Bureau Veritas Certification certify that the Quality Management System of the above organisation has been audited and found to be in accordance with the requirements of

## IATF 16949 - FIRST EDITION

and the applicable customer specific requirements



**SCOPE** 

Design and manufacturing PERMITTED EXCLUSION(S)

None

PRODUCT(S) DELIVERED

**Integrated Circuits** 

Date Of Certification: **02-July-2024**Date Of Expiration: **01-July-2027** 

IATF Certificate N°: **0528250** 

Bureau Veritas Certification Certificate No: USA-23131/18 - IATF

Revision: 1



For Bureau Veritas Certification Holding, Tour ALTO, 4 place des saisons, 92400 COURBEVOIE - France (The official document is in English. Any translations of this document shall be used for reference only.)





# Appendix to the Certificate of Approval

### **AWARDED TO**

# Texas Instruments, Inc. - LFAB

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#### REMOTE SUPPORT FUNCTION(S)

NAME	ADDRESS	SCOPE
Texas Instruments, Inc North Campus Support	13121 TI Blvd Dallas, TX 75243 United States IATF USI: 6E9WYZ	Purchasing, Laboratory, Process Design, Supplier Management, Logistics
Texas Instruments, Inc Semiconductor Group Headquarters - South Campus	12500 TI Blvd. Dallas, TX 75243 United States IATF USI: 3E9YYA	Policy Making, Strategic Planning, Marketing, Quality System Management, Human Resources, Information Technologies, Engineering, Laboratory, Product Design, Internal Audit Management
Texas Instruments, Inc TMG Top Management	13121 TI Blvd. Dallas, TX 75243 United States IATF USI: CF99Y6	Strategic Planning, Policy Making

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